

**NEW** Preview

Renewal of HIOKI's world-leading battery tester







## Designing automatic battery testing systems is easier and faster than ever before

- Double the total line resistance, so measurement errors are less likely to occur when using long measurement cables
- Stable operation regardless of increased total line resistance due to probe and relay degradation
- LAN is equipped as a standard for easy system design and layout, and excellent noise resistance for stable operation



## Lineup

Model			Acceptance inspection of general-purpose, small cells installed in a high-speed sorters  3561, 3561-01	or small packs of up to 60 V	Fully automated production line testing of large cells for xEVs or mid-size packsup of to 100 V  BT3562A  NEW	Fully automated production line testing of large packs for xEVs or large packs up of to 300 V BT3563A  NEW
ppearance				BT3561A  NEW		
Measurement method			AC four-terminal method	AC four-terminal method	AC four-terminal method	AC four-terminal method
Resistance assurement		3 mΩ	N/A	N/A	$3.1000~\text{m}\Omega,0.1~\mu\Omega,100~\text{m}A$	3.1000 mΩ, 0.1 μΩ, 100 m
		30 mΩ	N/A	31.000 mΩ, 1 μΩ, 100 mA	31.000 m $\Omega$ , 1 $\mu\Omega$ , 100 mA	31.000 mΩ, 1 μΩ, 100 m.
		300 mΩ	310.00 m $\Omega$ ,10 $\mu\Omega$ , 10 mA	310.00 mΩ,10 μΩ, 10 mA	310.00 m $\Omega$ ,10 $\mu\Omega$ , 10 mA	310.00 mΩ,10 μΩ, 10 m/
		3 Ω	3.1000 Ω,100 μΩ, 1 mA	3.1000 Ω,100 μΩ, 1 mA	$3.1000~\Omega,100~\mu\Omega,~1~mA$	3.1000 Ω,100 μΩ, 1 mA
Ĭ		30 Ω	N/A	31.000 Ω, 1 mΩ, 100 μΑ	31.000 Ω, 1 mΩ, 100 μΑ	31.000 Ω, 1 mΩ, 100 μΑ
Max. display,		300 Ω	N/A	310.00 Ω, 10 mΩ, 10 μΑ	310.00 Ω, 10 mΩ, 10 μΑ	310.00 Ω, 10 mΩ, 10 μΑ
resolution, measurement		3 kΩ	N/A	3.1000 kΩ, 100 mΩ, 10 μΑ	3.1000 kΩ, 100 mΩ, 10 μA	3.1000 kΩ, 100 mΩ, 10 μ
measurement current  Voltage	Basic	3 mΩ range	N/A	N/A	±0.5% rdg. ±10 dgt.	±0.5% rdg. ±10 dgt.
	accuracy	30 mΩ range or more	±0.5% rdg. ±5 dgt.	±0.5% rdg. ±5 dgt.	±0.5% rdg. ±5 dgt.	±0.5% rdg. ±5 dgt.
		6 V	N/A	6.00000 V,10 μV	6.00000 V,10 μV	6.00000 V, 10 μV
Voltage		20 V	19.9999 V, 100 μV	N/A	N/A	N/A
measurement		60 V	N/A	60.0000 V, 100 μV	60.0000 V, 100 μV	60.0000 V, 100 μV
ranges		100 V	N/A	N/A	100.000 V, 1 mV	N/A
		300 V	N/A			
Max. display, resolution				N/A	N/A	300.000 V, 1 mV
		1000 V	N/A	N/A	N/A	N/A
Basic accuracy		±0.01% rdg. ±3 dgt. *1	±0.01% rdg. ±3 dgt.	±0.01% rdg. ±3 dgt.	±0.01% rdg. ±3 dgt.	
Response time *2			3 ms	10 ms	10 ms	10 ms
ampling period *3		Ω or V	4 ms, 12 ms, 35 ms, 150 ms	4 ms, 12 ms, 35 ms, 150 ms	4 ms, 12 ms, 35 ms, 150 ms	4 ms, 12 ms, 35 ms, 150 n
X.FAST, FAST, MED		ΩV	7 ms, 23 ms, 69 ms, 252 ms	8 ms, 24 ms, 70 ms, 253 ms	8 ms, 24 ms, 70 ms, 253 ms	8 ms, 24 ms, 70 ms, 253 n
Mithin accuracy) anges: 3 mΩ, 30 mΩ, 300 mΩ, 3 Ω		SENSE line	Ν/Α, Ν/Α, 20 Ω, 20 Ω	Ν/Α, 4 Ω, 30 Ω, 30 Ω	4 Ω, 4 Ω, 30 Ω, 30 Ω	4 Ω, 4 Ω, 30 Ω, 30 Ω
		SOURCE line	N/A, N/A, 20 $\Omega$ , 20 $\Omega$	Ν/Α, 4 Ω, 20 Ω, 40 Ω	4 $\Omega$ , 4 $\Omega$ , 20 $\Omega$ , 40 $\Omega$	4 Ω, 4 Ω, 20 Ω, 40 Ω
llowable total line re	esistance *2 *4	SENSE line	Ν/Α, Ν/Α, 20 Ω, 20 Ω	Ν/Α, 6 Ω, 30 Ω, 30 Ω	6 Ω, 6 Ω, 30 Ω, 30 Ω	6 Ω, 6 Ω, 30 Ω, 30 Ω
error detection) anges: 3 mΩ, 30 mΩ, 3	300 mΩ, 3 Ω	SOURCE line	Ν/Α, Ν/Α, 20 Ω, 20 Ω	Ν/Α, 6 Ω, 20 Ω, 200 Ω	6 Ω, 6 Ω, 20 Ω, 200 Ω	6 Ω, 6 Ω, 20 Ω, 200 Ω
Open terminal voltage Ranges: 30 mΩ or less, 300 mΩ, 3 $\Omega$ or more		N/A, 7 V, 7 V peak	25 V, 7 V, 4 V peak	25 V, 7 V, 4 V peak	25 V, 7 V, 4 V peak	
LAN (TCP/IP, 10BASE-T/100BASE-TX)			N/A	V	<b>V</b>	V
RS-232C *5 (Max. 38.4 kbps)			✓ (9.6 kbps fixed)	V	<b>V</b>	V
USB		N/A	N/A	N/A	N/A	
GP-IB		✓ (3561-01 Only)	N/A	N/A	N/A	
EXT. I/O (37-pin Handler interface)		<i>V</i>	V	V	V	
Analog output (DC 0 V to 3.1 V)			N/A	V	<i>V</i>	<i>V</i>
Contact check			· · · · · · · · · · · · · · · · · · ·	V		<i>V</i>
Zero adjustment (±1000 counts)				· ·	· · · · · · · · · · · · · · · · · · ·	~
Pulse mesurement			V			
- Comparator			Hi/ IN/ Lo	Hi/ IN/ Lo	Hi/ IN/ Lo	Hi/ IN/ Lo
Statistical calculations  Delay			Max. 30,000	Max. 30,000	Max. 30,000	Max. 30,000
Delay		Wax. 30,000 ✓	Wax. 30,000 ✓	Wax. 30,000 ✓	Wax. 30,000 ✓	
Average		· · · · · · · · · · · · · · · · · · ·	·	·	·	
			2 to 16 times	2 to 16 times	2 to 16 times	2 to 16 times
Panel saving/loading  Memory storage			126	126	126	126
LabVIEW® driver '6			400 N/A	400	400	400
Applicable standards			N/A Safety: EN61010	Safety: EN61010	Safety: EN61010	Safety: EN61010
Effect of radiated radio-frequency			EMC: EN61326 Class A	EMC: EN61326 Class A	EMC: EN61326 Class A	EMC: EN61326 Class /
lectromagnetic fiel	ld (10 V/m) *	7	Resistant	Resistant	Resistant	Resistant
frequency electromagnetic field ——		10 V	N/A	Resistant	Resistant	Resistant
	0.15 MHz to 80 MHz, 80% AM 3 V CE		Resistant	Resistant	Resistant	Resistant
			<i>V</i>	V	V	V





<sup>\*1:</sup> rdg. stands for reading, dgt. stands for digits \*2: Typical value \*3: When the power supply frequency is 60 Hz
\*4: Total line resistance = wiring resistance + contact resistance + DUT resistance \*5: Available as printer I/F
\*6: LabVIEW® Driver is a registered trademark of National Instruments Corporation \*7: Test conditions were 80 MHz to 1 GHz at 10 V/m and 1 GHz to 6 GHz at 3 V/m, all at 80% AM
\*8: Canadian Standards Assosiation